

## Physics and stack engineering of ultra-small magnetic tunnel junctions using shape anisotropy

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Shape-anisotropy magnetic tunnel junction (MTJ) <sup>[1]</sup> is attracting much attention for future-generation spin-transfer torque magnetoresistive random access memory (STT-MRAM) because of its scalability into the X/1X nm regime. Making a cylindrical nanomagnet with its thickness ( $t$ ) larger than its diameter ( $D$ ) allows one to positively combine shape anisotropy and interfacial anisotropy, resulting in a high thermal stability factor  $\Delta$  ( $\equiv E/k_B T$ , where  $E$  is the energy barrier between the two magnetization states,  $k_B$  is the Boltzmann constant, and  $T$  is a temperature) even at the X/1X nm regime <sup>[1,2]</sup>. STT switching has also been demonstrated in such small and stable MTJs <sup>[1]</sup>. Understanding the change in  $E$  at high temperatures is of significant interest from both fundamental and applications points of view. In this study, we investigate the temperature dependence of  $E$  in the X/1X nm shape-anisotropy MTJs and show designs compatible with applications at high temperatures.

We evaluate  $\Delta$  at various temperatures up to 191 °C for MTJs with  $D$  ranging from 5.0 to 11.9 nm by measuring the switching probability using a pulsed magnetic field. We find that the scaling relationship between the temperature dependence of spontaneous magnetization and  $E$  ( $= \Delta k_B T$ ) for the shape-anisotropy MTJs is well described by a model assuming a dominant contribution of shape anisotropy. Based on the obtained scaling relationship, we also discuss a window of shape-anisotropy MTJ for high-temperature applications below 20 nm <sup>[3]</sup>.

In the presentation, we also present our latest results on shape-anisotropy MTJs employing a multilayered ferromagnetic structure (Fig. 1), showing notable performance in X-nm regime: (1) stable switching and high  $\Delta$  at high temperatures, (2) switching efficiency improvement, and (3) high speed STT switching with a 10-ns pulse below 1 V <sup>[4]</sup>.

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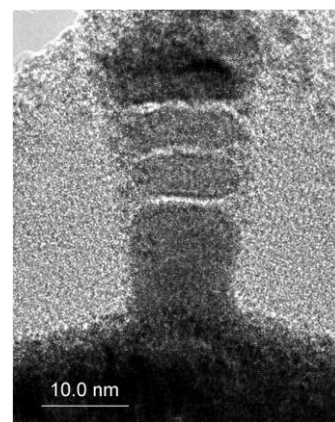


Fig. 1 Cross-sectional TEM image for the shape-anisotropy MTJ employing multilayered ferromagnetic structure.